

1 **IN THE CLAIMS**

2
3 **Please amend Claim 1 as follows.**

4
5 1. **(Currently Amended)** A memory unit comprising:
6 a memory portion having storage units for storing
7 data bits;
8 a memory portion for storing error correction
9 bits;
10 an error checking and correction unit; and
11 registers to hold the location of one or more
12 corrected bits;
13 wherein the error checking and correction unit
14 includes circuitry for requesting an interrupt and/or for
15 setting a flag which is polled, when a memory location of a
16 failing bit is correctable.

17
18 **Please cancel Claim 2.**

19
20 2. **(Cancelled)** ~~The memory unit as recited in~~
21 ~~claim 1 wherein the error checking and correction unit~~
22 ~~includes circuitry for requesting an interrupt and/or for~~
23 ~~setting a flag which can be polled, when a failing bit can~~
24 ~~be corrected.~~

25
26 **Please amend Claim 3 as follows.**

27
28 3. **(Currently Amended)** The memory unit as recited in
29 claim 1 wherein the error detection and correction unit
30 includes circuitry for requesting an abort condition when a

1 failing bit memory location is detected which can not be
2 corrected.

3
4 **Please amend Claim 4 as follows.**

5
6 4. (**Currently Amended**) The memory unit as recited in
7 claim 2 3 wherein the memory is composed of storage units
8 storing data bits that ~~can be~~ are set to one of two states,
9 wherein any of the data bits ~~may be~~ are changed to a first
10 state independently of the other bits, the resulting state
11 being a programmed state, wherein all of the data bits of a
12 plurality of data bits must be set to the second state
13 simultaneously, the second state being an erased state, the
14 memory unit further comprising:

15 circuitry to store the location of a correctable
16 memory location error; and

17 circuitry to generate an interrupt request;

18 circuitry to set a flag bit only when the correctable
19 memory location error is a bit that has been changed from
20 the programmed state to the erased state.

21
22 **Please withdraw Claim 5.**

23
24 5. (**Withdrawn**) A memory unit comprising:
25 storage units storing data bits;
26 storage units storing error checking and correction
27 bits; and

28 an error detection and correction unit wherein the
29 memory unit contains circuitry to optionally exclude the
30 condition where all of the data bits and error detection

1 and correction bits are in the erased state from generating
2 bit correction.

3
4 **Please withdraw Claim 6.**

5
6 6. **(Withdrawn)** A memory unit comprising:
7 storage units for storing data bits;
8 storage units for storing error correction bits;
9 an error detection and correction unit;
10 circuitry to optionally exclude the condition
11 where all of the data bits and error detection and
12 correction bits are in the programmed state from generating
13 bit correction.

14
15 **Please amend Claim 7 as follows.**

16
17 7. **(Currently Amended)** A data processing system, the
18 data processing system comprising:
19 a central processing unit; and
20 a memory unit, the memory unit including:
21 a main memory, the main memory storing data
22 signal groups in a plurality of addresses;
23 an error checking and correction memory, the
24 error checking and correction memory storing error
25 correcting signals for each data signal group in the main
26 memory at the same address in the error checking and
27 correction code memory;
28 an error checking and correction apparatus
29 for identifying and correcting at least one error in a

1 memory location of a data group accessed by a read
2 operation; and

3 a failing bit apparatus, the failing bit
4 apparatus identifying when a correctable error is the
5 result of a failing bit memory location.

6
7 **Please amend claim 8 as follows.**

8
9 8. **(Currently Amended)** The data processing system as
10 recited in claim 7 wherein the failing bit apparatus
11 includes:

12 an address storage unit;
13 a correction pattern storage unit; and
14 an interrupt flag unit, the interrupt flag unit
15 issuing an interrupt flag when an error is detected that
16 ~~can be~~ is the result of failing bit memory location.

17
18 9. **(Original)** The data processing system as
19 recited in claim 8 further comprising an all logic "1"s
20 detection unit for determining whether all of the signals
21 from a main memory and error checking and correction memory
22 are all logic "1".

23
24 10. **(Original)** The data processing system as
25 recited in claim 7 wherein the main memory and the error
26 checking and correction memory are implemented in a
27 technology selected from the group consisting of flash
28 technology and EEPROM technology.

1 **Please withdraw claim 11.**

2
3 11. **(Withdrawn)** A method of responding to an
4 error in a signal group retrieved from a non-volatile
5 memory unit, the method comprising:

6 when the error is correctable, correcting the
7 error in the signal group using error checking and
8 correction techniques; and

9 when the error is consistent with a failing bit
10 position, restoring the charge associated with the bit
11 position.

12
13 **Please withdraw Claim 12.**

14
15 12. **(Withdrawn)** The method as recited in claim 11
16 wherein the restoring step includes the steps of:

17 storing the address of the signal group having
18 the error;

19 storing the correction pattern identifying
20 location of the error in the signal group; and

21 providing an interrupt flag to the central
22 processing unit indicating the need to restore a bit
23 location in the memory unit.

24
25 **Please withdraw Claim 13.**

26
27 13. **(Withdrawn)** The method as recited in claim 11
28 further comprising implementing the main memory and the
29 error checking and correction memory in a technology

1 selected from the group consisting of flash technology and
2 EEPROM technology.

3
4 **Please amend Claim 14 as follows.**

5
6 14. **(Currently Amended)** A memory unit comprising:
7 a non-volatile main memory unit;
8 a non-volatile error memory for storing error
9 checking and correction signals for a signal group in the
10 main memory having the same address;
11 an error checking and correction apparatus, the
12 error apparatus generating a correction pattern identifying
13 the location of an error in an addressed signal group and
14 the associated error signals, the error apparatus
15 generating a restore signal when the error is consistent
16 with a failing bit location;
17 a flag apparatus storing the associated
18 correction pattern and the associated address in response
19 to the restore signal, the flag apparatus generating an
20 interrupt flag in response to the restore signal.

21
22 **Please amend Claim 15 as follows.**

23
24 15. **(Currently Amended)** The memory unit as recited
25 in claim 14 wherein the stored correction pattern and the
26 stored address are transferred to the central processor for
27 restoration of the failing bit memory location when the
28 central processing unit services the interrupt.

1 16. **(Original)** The memory unit as recited in
2 claim 14 wherein the error checking and correction
3 apparatus includes an all logic "1"s detection unit, the
4 all logic "1"s detection unit determining when the signals
5 stored in the main memory and in the error signal memory
6 are all logic "1"s.

7
8 17. **(Original)** The memory unit as recited in
9 claim 14 wherein the main memory and the error checking and
10 correction memory are implemented in a technology selected
11 from the group consisting of flash technology and EEPROM
12 technology.